

<b>Notice of References Cited</b>	Application/Control No. 09/989,812	Applicant(s)/Patent Under Reexamination NEMECEK ET AL.	
	Examiner Dwin M Craig	Art Unit 2123	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,499,122 B1	12-2002	Coomes, Joseph A.	714/724
*	B	US-5,640,337	06-1997	Huang et al.	703/23
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B. Laquai, H. Richter, H. Werkmann, "A Production-oriented Measurement Method for Fast and Exhaustive Iddq Tests", IEEE 1997, pages 279-286.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.